Search Notes

	Application/Control No.	Applicant(s)/Patent und Reexamination	er
1	10/686,311	NAGY ET AL.	
Γ	Examiner	Art Unit	
	Rip A. Lee	1713	

SEARCHED					
Class	Subclass	Date	Examiner		
526	172	05-17-2005	~		
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
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